Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/662,857	EYER, MARK KENNETH
Examiner	Art Unit

Matsuichiro Shimizu

2612

SEARCHED						
Class	Subclass	Date	Examiner			
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
		DATE	EXMR		
Gaston	340,341	10/7/06	Wo		